

IEEE EDS Kansai Chapter Awards 2020

■ IEEE EDS Kansai Chapter of the Year Award

Author: **Ryutaro Yasuhara**
Title: Reliability Issues in Analog ReRAM Based Neural-Network Processor
Coauthors: T. Ono, R. Mochida, S. Muraoka, K. Kouno, K. Katayama, Y. Hayata, M. Nakayama, H. Suwa, Y. Hayakawa, T. Mikawa, Y.Gohou, and S. Yoneda
Affiliation: Nuvoton Technology Corporation Japan

■ IEEE EDS Kansai Chapter MFSK Award

Author: **Kunihiro Oshima**
Title: Experimental study of bias stress degradation of organic thin film transistors
Coauthors: M. Saito, M.Shintani,K. Kuribara, Y. Ogasahara, and T.Sato
Affiliation: Kyoto University

Author: **Takashi Hamano**
Title: Effects of Variability in Plasma-Induced Damage to Si Substrate on Device Performance and Its Application to Variability Assessment Methodology
Coauthors: K. Urabe, K. Eriguchi
Affiliation: Kyoto University